

SEMICONDUCTORIM

December 1994 Revised September 2000

## 74F00

# **Quad 2-Input NAND Gate**

## **General Description**

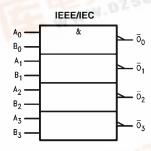
This device contains four independent gates, each of which performs the logic NAND function.

#### **Ordering Code:**

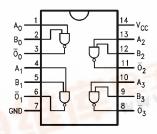
Order Number	Package Number	Package Description
74F00SC	M14A	14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150 Narrow
74F00SJ	M14D	14-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74F00PC	N14A	14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

#### **Logic Symbol**



#### **Connection Diagram**



## **Unit Loading/Fan Out**

Pin Names	Description	U.L.	Input I <sub>IH</sub> /I <sub>IL</sub>		
Pin Names	Description	HIGH/LOW	Output I <sub>OH</sub> /I <sub>OL</sub>		
A <sub>n</sub> , B <sub>n</sub>	Inputs	1.0/1.0	20 μA/-0.6 mA		
$\overline{O}_n$	Outputs	50/33.3	−1 mA/20 mA		



#### **Absolute Maximum Ratings**(Note 1)

Storage Temperature -65°C to +150°C

Ambient Temperature under Bias  $-55^{\circ}C$  to  $+125^{\circ}C$ Junction Temperature under Bias  $-55^{\circ}$ C to  $+150^{\circ}$ C V<sub>CC</sub> Pin Potential to Ground Pin -0.5V to +7.0V

Input Voltage (Note 2) -0.5V to +7.0V Input Current (Note 2) -30 mA to +5.0 mA

Voltage Applied to Output

in HIGH State (with  $V_{CC} = 0V$ )

Standard Output -0.5V to  $V_{CC}$ 3-STATE Output -0.5V to +5.5V

Current Applied to Output

in LOW State (Max) twice the rated  $I_{OL}$  (mA) 4000V

ESD Last Passing Voltage (Min)

### **Recommended Operating Conditions**

Free Air Ambient Temperature 0°C to +70°C +4.5V to +5.5V Supply Voltage

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation

under these conditions is not implied.

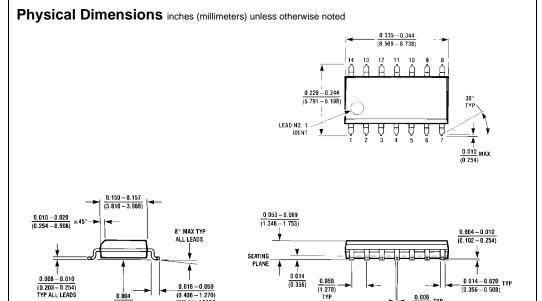
Note 2: Either voltage limit or current limit is sufficient to protect inputs.

#### **DC Electrical Characteristics**

Symbol	Parameter		Min	Тур	Max	Units	v <sub>cc</sub>	Conditions		
V <sub>IH</sub>	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal		
V <sub>IL</sub>	Input LOW Voltage				0.8	V		Recognized as a LOW Signal		
V <sub>CD</sub>	Input Clamp Diode Voltage				-1.2	V	Min	I <sub>IN</sub> = -18 mA		
V <sub>OH</sub>	Output HIGH 1	0% V <sub>CC</sub>	2.5			V	Min	I <sub>OH</sub> = -1 mA		
	Voltage 5	% V <sub>CC</sub>	2.7					$I_{OH} = -1 \text{ mA}$		
V <sub>OL</sub>	Output LOW 1	0% V <sub>CC</sub>			0.5	V	Min	I <sub>OL</sub> = 20 mA		
	Voltage									
I <sub>IH</sub>	Input HIGH				5.0	μΑ	Max	$V_{IN} = 2.7V$		
	Current									
I <sub>BVI</sub>	Input HIGH Current				7.0	μΑ	Max	$V_{IN} = 7.0V$		
	Breakdown Test									
I <sub>CEX</sub>	Output HIGH				50	μΑ	Max	$V_{OUT} = V_{CC}$		
	Leakage Current									
V <sub>ID</sub>	Input Leakage Test		4.75			٧	0.0	I <sub>ID</sub> = 1.9 μA		
								All other pins grounded		
I <sub>OD</sub>	Output Leakage Circuit Current				3.75	μА	0.0	V <sub>IOD</sub> = 150 mV		
					5.75			All other pins grounded		
I <sub>IL</sub>	Input LOW Current				-0.6	mA	Max	V <sub>IN</sub> = 0.5V		
Ios	Output Short-Circuit Current		-60		-150	mA	Max	V <sub>OUT</sub> = 0V		
I <sub>CCH</sub>	Power Supply Current			1.9	2.8	mA	Max	V <sub>O</sub> = HIGH		
I <sub>CCL</sub>	Power Supply Current			6.8	10.2	mA	Max	$V_O = LOW$		

#### **AC Electrical Characteristics**

Symbol	Parameter	$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$			$T_{A} = -55^{\circ}\text{C to } +125^{\circ}\text{C}$ $V_{CC} = +5.0\text{V}$ $C_{L} = 50 \text{ pF}$		$T_A = 0$ °C to $+70$ °C $V_{CC} = +5.0$ V $C_L = 50$ pF		Units
		Min	Тур	Max	Min	Max	Min	Max	
t <sub>PLH</sub>	Propagation Delay	2.4	3.7	5.0	2.0	7.0	2.4	6.0	ns
t <sub>PHL</sub>	$A_n$ , $B_n$ to $\overline{O}_n$	1.5	3.2	4.3	1.5	6.5	1.5	5.3	115

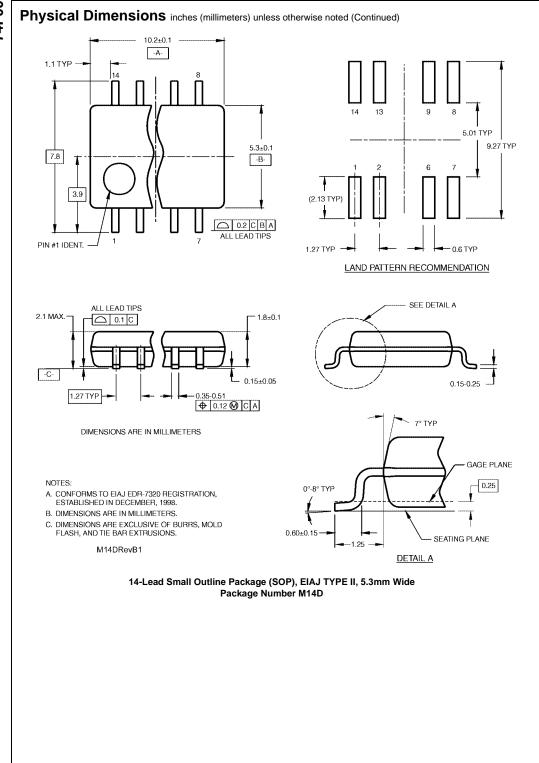


14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150 Narrow Package Number M14A

0.016 - 0.050 (0.406 - 1.270) TYP ALL LEADS

 $\frac{0.014 - 0.020}{(0.356 - 0.508)} \, \text{TYP}$ 

0.008 (0.203) TYP



#### Physical Dimensions inches (millimeters) unless otherwise noted (Continued) (18.80 - 19.56)0.090 (2.286) 14 13 12 11 10 9 14 13 12 $0.250 \pm 0.010$ (6.350 ± 0.254) PIN NO. 1 IDENT PIN NO. 1 IDENT 1 2 3 4 5 6 7 1 2 3 $\frac{0.092}{(2.337)}$ DIA $\frac{0.030}{(0.762)}$ MAX OPTION 1 OPTION 02 $0.135 \pm 0.005$ 0.300 - 0.320 $(3.429 \pm 0.127)$ (7.620 - 8.128)0.065 0.145 - 0.2000.060 4° TYP Optional (1.651) (1.524)(3.683 - 5.080)0.008-0.016 TYP (0.203 - 0.406)(0.508) MIN 0.125 - 0.150 $0.075 \pm 0.015$ 0.280 (7.112) MIN 0.014-0.023 TYP $\frac{0.100 \pm 0.010}{(2.540 \pm 0.254)} \text{ TYP}$ (0.356 - 0.584) $\frac{0.050\pm0.010}{(1.270-0.254)} \text{ TYP}$ 0.325 +0.040 -0.015

14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N14A

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- A critical component in any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

8.255 + 1.016 - 0.381

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N14A (REV F)